

WHAT IS CLAIMED IS:

1. A quality assurance automatic display system comprising:

5 a data processor having an inspection item data hold section and a data processing section;

the inspection item data hold section holding inspection item graded data which have been graded by determination of reliability of a per-inspection-item for a substance to be inspected; and

10 the data processing section determining general graded data pertaining to the degree of quality assurance of the substance in accordance with an algorithm employed in the data processing section after having received the inspection item graded data from the inspection item data hold section; and

15 a display device for displaying the general graded data transported from the data processing section.

20 2. The quality assurance automatic display system according to claim 1, wherein the data processor further comprises an inspection data hold section for holding inspection data pertaining to the substance for each of the inspection items, and the general graded data are determined in the data
25 processing section on the basis of both the inspection item graded data and the inspection data transported from the inspection data hold section

30 3. The quality assurance automatic display system according to claim 1, wherein the inspection item graded data are produced as a result of a determination being made by means of taking, as references, an inspection apparatus and an

inspection method corresponding to the inspection item.

4. The quality assurance automatic display system
according to claim 1, wherein the display device is a printer
5 which prints the general graded data directly onto the substance.

5. The quality assurance automatic display system
according to claim 1, wherein the substance to be inspected
corresponds to a semiconductor device, a photomask, or photomask
10 indirect material.

6. The quality assurance automatic display system
according to claim 1, wherein the substance to be inspected
2 is a photomask, and the display device is constructed so as
15 to provide the general graded data on an area within a pattern
region on the photomask in which no pattern is to be formed.